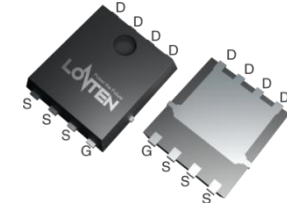
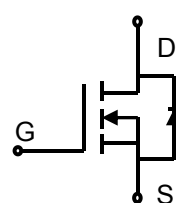



Lonten N-channel 40V, 160A, 1.35mΩ Power MOSFET

<p>Description These N-Channel enhancement mode power field effect transistors are using shielded gate trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and with stand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.</p> <p>Features</p> <ul style="list-style-type: none"> ◆ 40V, 160A, $R_{DS(on).max} = 1.35m\Omega @ V_{GS} = 10V$ ◆ Improved dv/dt capability ◆ Fast switching ◆ 100% EAS Guaranteed ◆ Green device available <p>Applications</p> <ul style="list-style-type: none"> ◆ DC-DC Converter ◆ Hard switching and high speed circuit 	<p>Product Summary</p> <table style="width: 100%; border: none;"> <tr> <td style="padding: 2px;">V_{DSS}</td> <td style="padding: 2px;">40V</td> </tr> <tr> <td style="padding: 2px;">$R_{DS(on).max} @ V_{GS} = 10V$</td> <td style="padding: 2px;">1.35mΩ</td> </tr> <tr> <td style="padding: 2px;">I_D</td> <td style="padding: 2px;">160A</td> </tr> </table> <p>Pin Configuration</p> <div style="text-align: center;">  <p>DFN5×6</p>  <p>N-Channel MOSFET</p> </div> <div style="text-align: right; margin-top: 10px;">  </div>	V_{DSS}	40V	$R_{DS(on).max} @ V_{GS} = 10V$	1.35mΩ	I_D	160A
V_{DSS}	40V						
$R_{DS(on).max} @ V_{GS} = 10V$	1.35mΩ						
I_D	160A						

Absolute Maximum Ratings T_c = 25°C unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	40	V
Continuous drain current ($T_c = 25^\circ C$) ($T_c = 100^\circ C$)	I_D	160	A
		101	A
Pulsed drain current ¹⁾	I_{DM}	480	A
Gate-Source voltage	V_{GSS}	± 20	V
Avalanche energy ²⁾	E_{AS}	676	mJ
Power Dissipation	P_D	69	W
Storage Temperature Range	T_{STG}	-55 to +150	°C
Operating Junction Temperature Range	T_J	-55 to +150	°C

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.8	°C/W
Thermal Resistance, Junction-to-Ambient ³⁾	$R_{\theta JA}$	65	°C/W

Package Marking and Ordering Information

Device	Device Package	Marking	Units/Reel
LSGN04R013WE	DFN 5×6	04R013WE	5000

Electrical Characteristics
 $T_J = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV_{DSS}	$V_{GS}=0\text{ V}, I_D=250\mu\text{A}$	40	---	---	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.2	---	2.0	V
Drain-source leakage current	I_{DSS}	$V_{DS}=40\text{ V}, V_{GS}=0\text{ V}, T_J = 25^\circ\text{C}$	---	---	1	μA
		$V_{DS}=40\text{ V}, V_{GS}=0\text{ V}, T_J = 150^\circ\text{C}$	---	---	10	mA
Gate leakage current, Forward	I_{GSSF}	$V_{GS}=20\text{ V}, V_{DS}=0\text{ V}$	---	---	100	nA
Gate leakage current, Reverse	I_{GSSR}	$V_{GS}=-20\text{ V}, V_{DS}=0\text{ V}$	---	---	-100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10\text{ V}, I_D=25\text{ A}, T_J = 25^\circ\text{C}$	---	1.15	1.35	m Ω
		$T_J = 150^\circ\text{C}$	---	2.1	---	
Forward transconductance	g_{fs}	$V_{DS} = 2\text{ V}, I_D=25\text{ A}$	---	90	---	S
Dynamic characteristics						
Input capacitance	C_{iss}	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 250\text{kHz}$	---	4020	---	pF
Output capacitance	C_{oss}		---	1140	---	
Reverse transfer capacitance	C_{rss}		---	31	---	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 20\text{V}, V_{GS}=10\text{V}, I_D = 50\text{ A}$	---	12	---	ns
Rise time	t_r		---	30	---	
Turn-off delay time	$t_{d(off)}$		---	79	---	
Fall time	t_f		---	38	---	
Gate charge characteristics						
Gate to source charge	Q_{gs}	$V_{DS}=32\text{ V}, I_D=50\text{A},$ $V_{GS}= 10\text{ V}$	---	12.4	---	nC
Gate to drain charge	Q_{gd}		---	14.3	---	
Gate charge total	Q_g		---	67	---	
Gate plateau voltage	$V_{plateau}$		---	3.5	---	V
Drain-Source diode characteristics and Maximum Ratings						
Continuous Source Current	I_S		---	---	57.5	A
Pulsed Source Current	I_{SM}		---	---	230	A
Diode Forward Voltage	V_{SD}	$V_{GS}=0\text{V}, I_S=50\text{A}, T_J=25^\circ\text{C}$	---	---	1.2	V
Reverse Recovery Time	t_{rr}	$I_S=50\text{A}, di/dt=100\text{A}/\mu\text{s},$ $T_J=25^\circ\text{C}$	---	50	---	ns
Reverse Recovery Charge	Q_{rr}		---	47	---	nC

Notes:

1: Repetitive Rating: Pulse width limited by maximum junction temperature.

 2: $V_{DD}=15\text{V}, L=0.5\text{mH}, I_{AS}=52\text{A}$, Starting $T_J=25^\circ\text{C}$.

3: Weld the device to a PCB board with the size of 32mm*36mm and then place it in an one-cubic-foot air static box.

Electrical Characteristics Diagrams

Figure 1. Typ. Output Characteristics

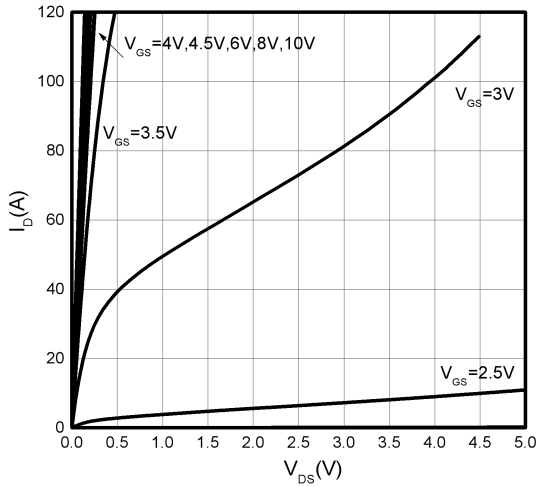


Figure 2. Transfer Characteristics

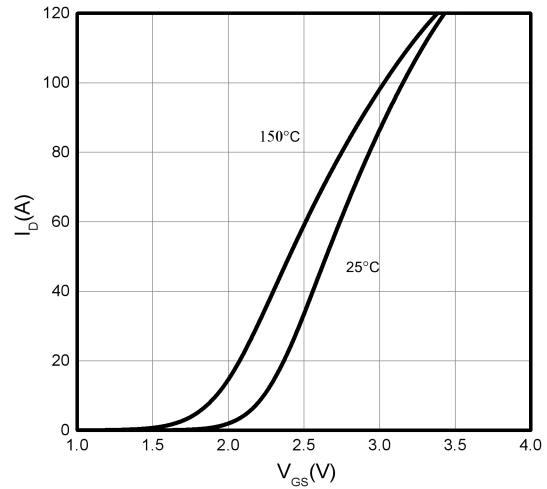


Figure 3. On-Resistance vs. Drain Current

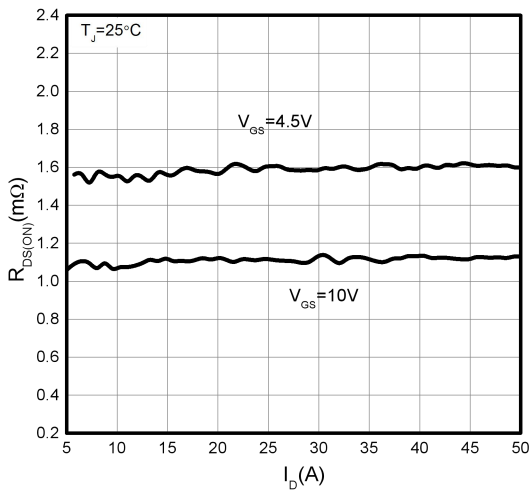


Figure 4. On-Resistance vs. Temperature

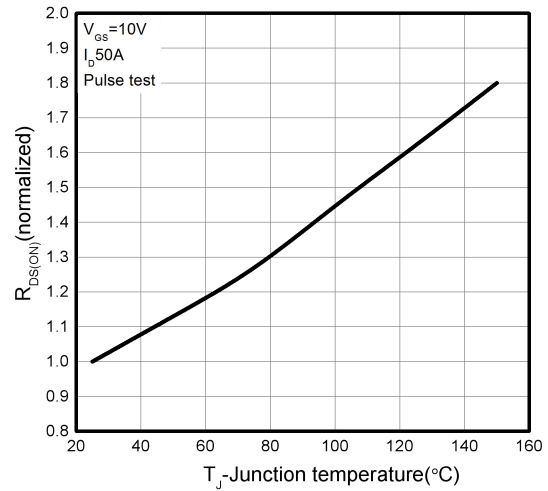


Figure 5. Breakdown Voltage vs. Temperature

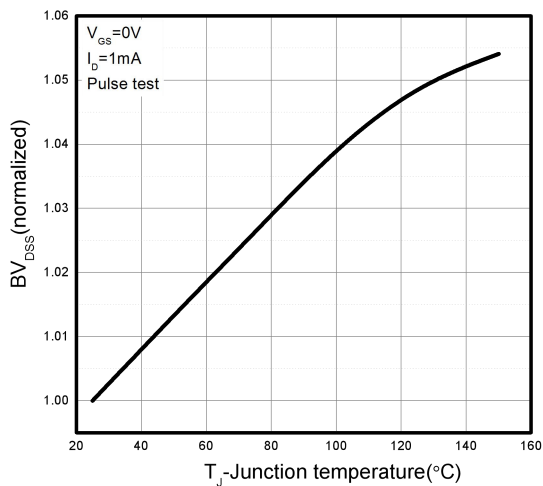


Figure 6. Threshold Voltage vs. Temperature

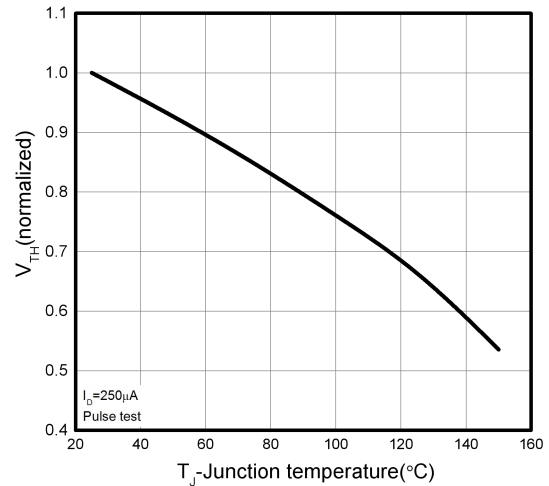


Figure 7. R_{DS(on)} vs. Gate Voltage

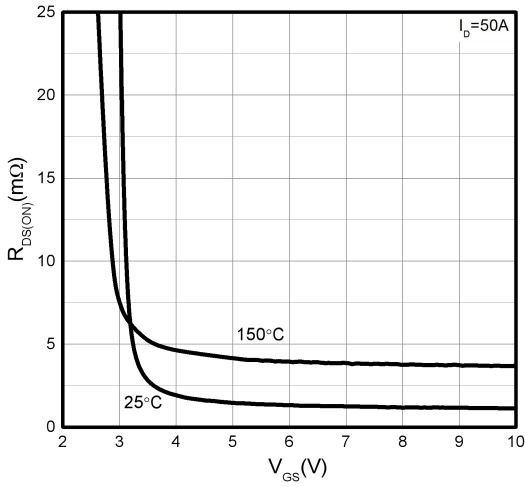


Figure 8. Body-Diode Characteristics

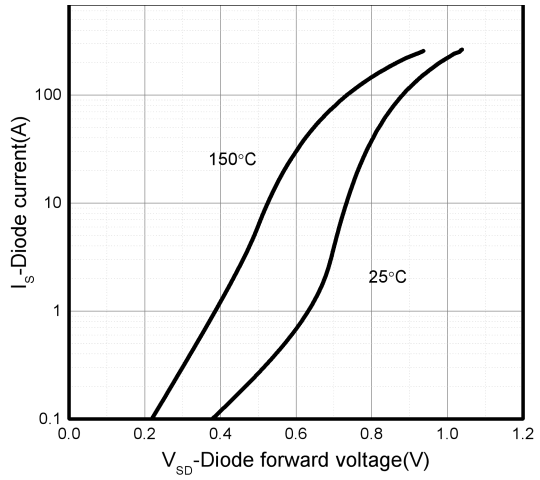


Figure 9. Capacitance Characteristics

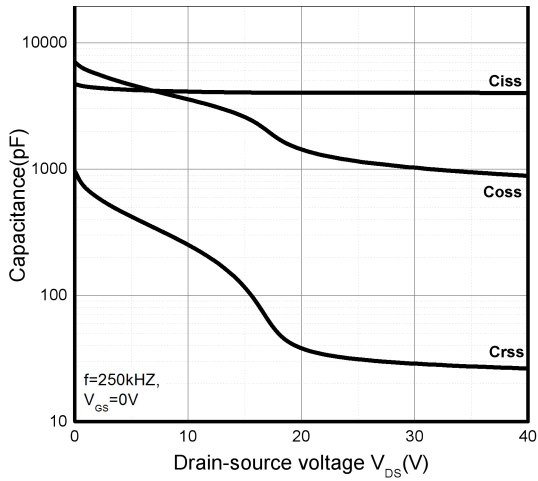


Figure 10. Gate Charge Characteristics

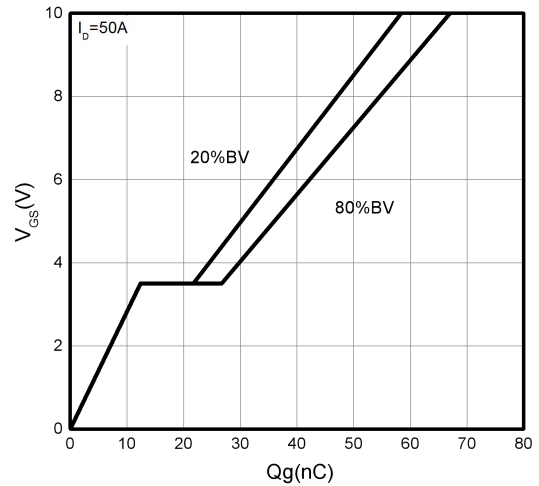


Figure 11. Drain Current Derating

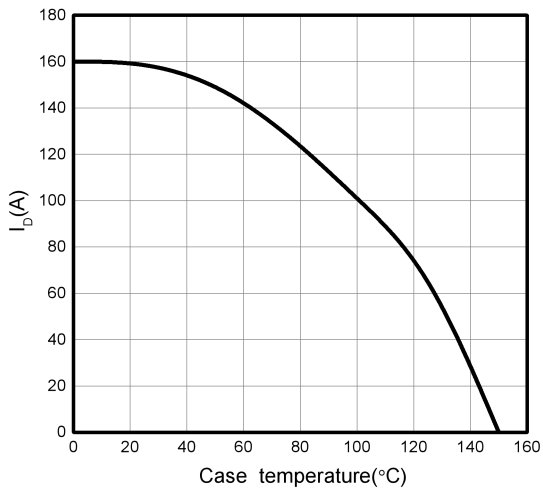


Figure 12. Power Dissipation vs. Temperature

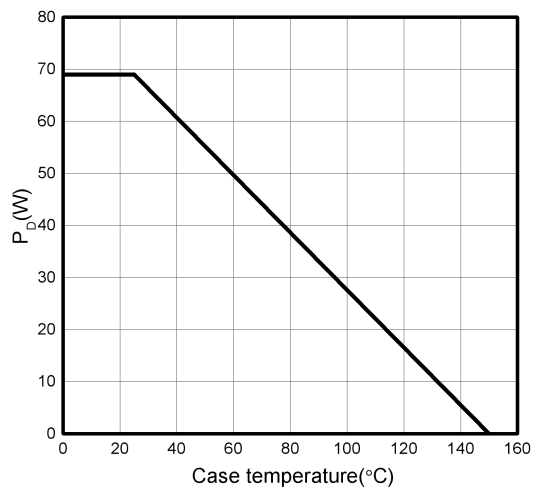


Figure 13: Safe Operating Area

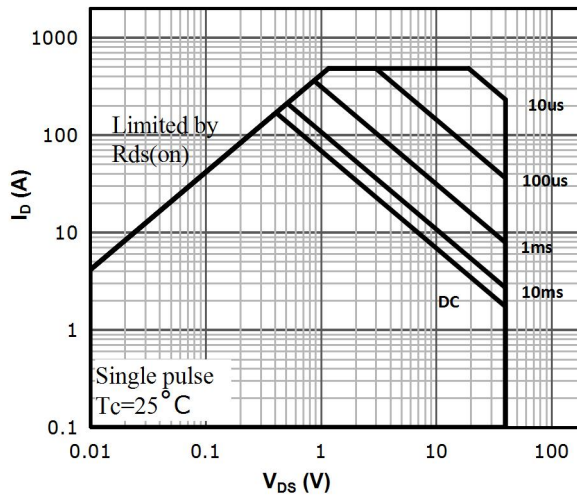
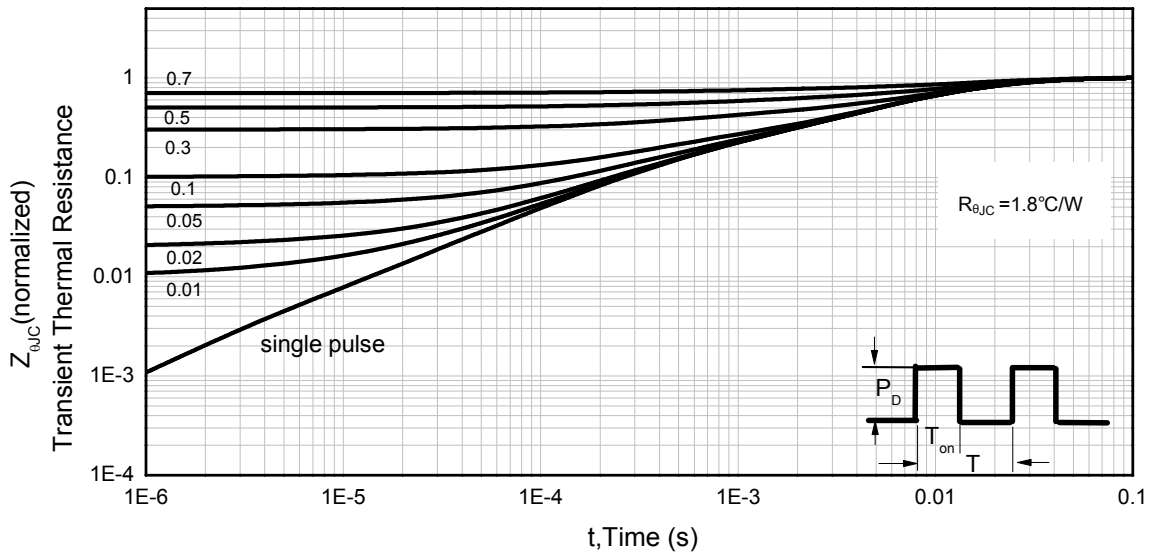
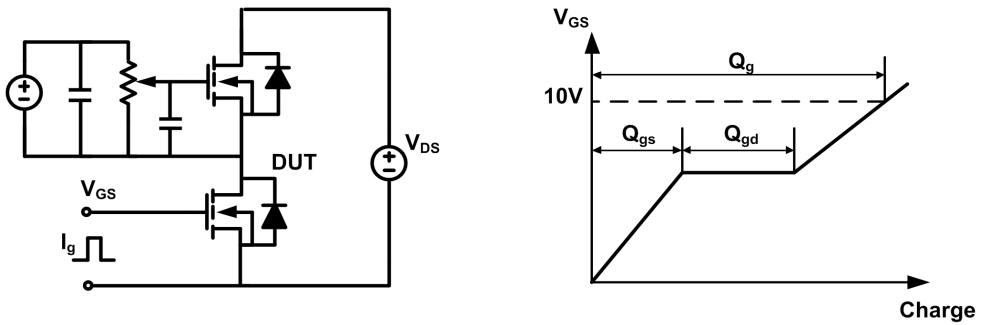


Figure 14. Normalized Maximum Transient Thermal Impedance (RthJC)

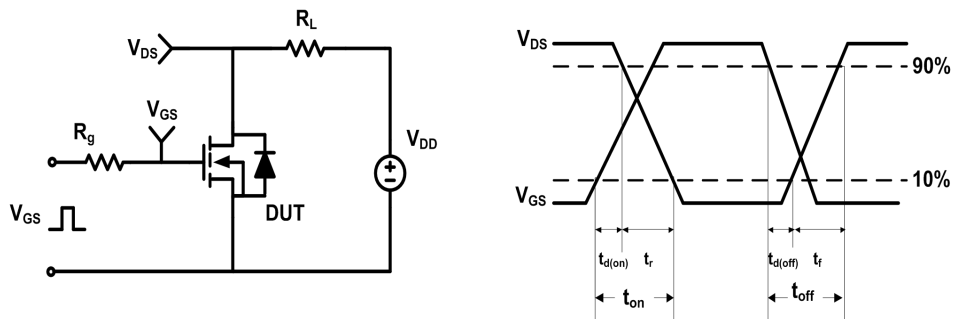


Test Circuit & Waveforms

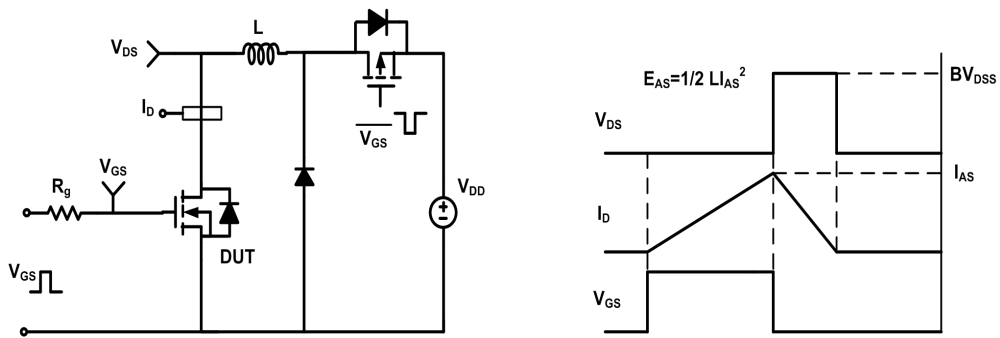
Gate Charge Test Circuit & Waveform



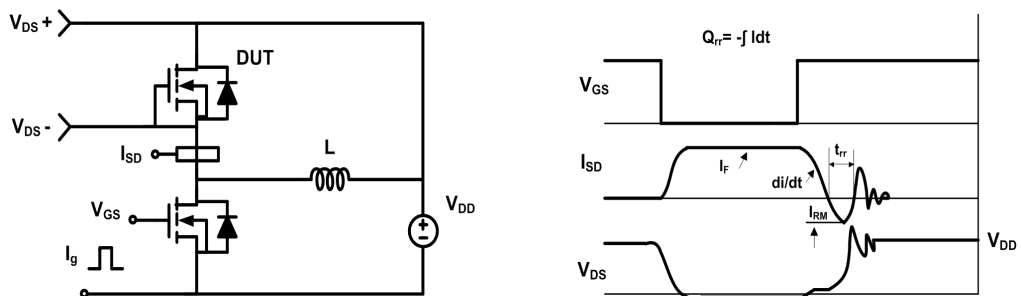
Resistive Switching Test Circuit & Waveform



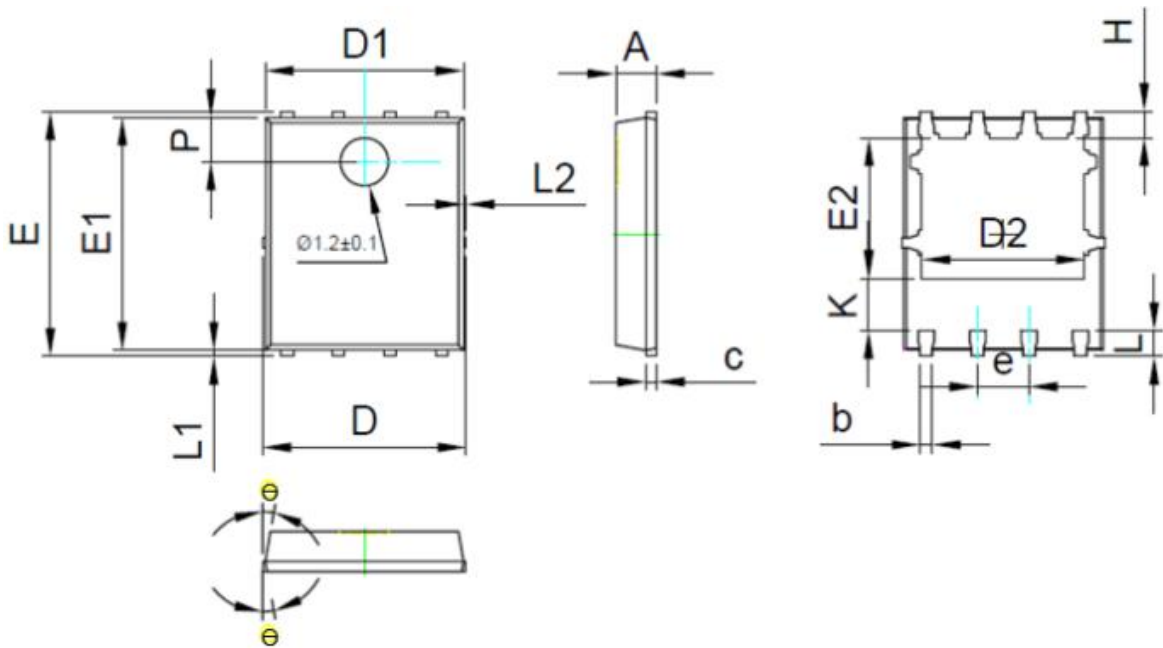
Unclamped Inductive Switching (UIS) Test Circuit & Waveform



Diode Recovery Test Circuit & Waveform



Mechanical Dimensions for DFN 5×6



SYMBOL	MIN	NOM	MAX
A	0.90	1.00	1.10
b	0.35	0.40	0.45
c	0.21	0.25	0.34
D	-	-	5.1
D1	4.85	4.90	4.95
D2	3.96	4.01	4.06
e	1.27 BSC		
E	5.95	6.00	6.05
E1	5.70	5.75	5.80
E2	3.425	3.475	3.525
H	0.60	0.65	0.70
K	1.29	-	-
L	0.60	0.65	0.70
L1	0.05	0.15	0.25
L2	-	-	0.12
θ	8°	10°	12°
P	1.05	1.10	1.15

Version Information

LSGN04R013WE

Revision:2021-10-15 ,Rev 0.1**Disclaimer**

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